



Istituto Nazionale di Fisica Nucleare

Sezione di Roma

The Service Board system

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Nobrega, Walter Rinaldi, LABE Support

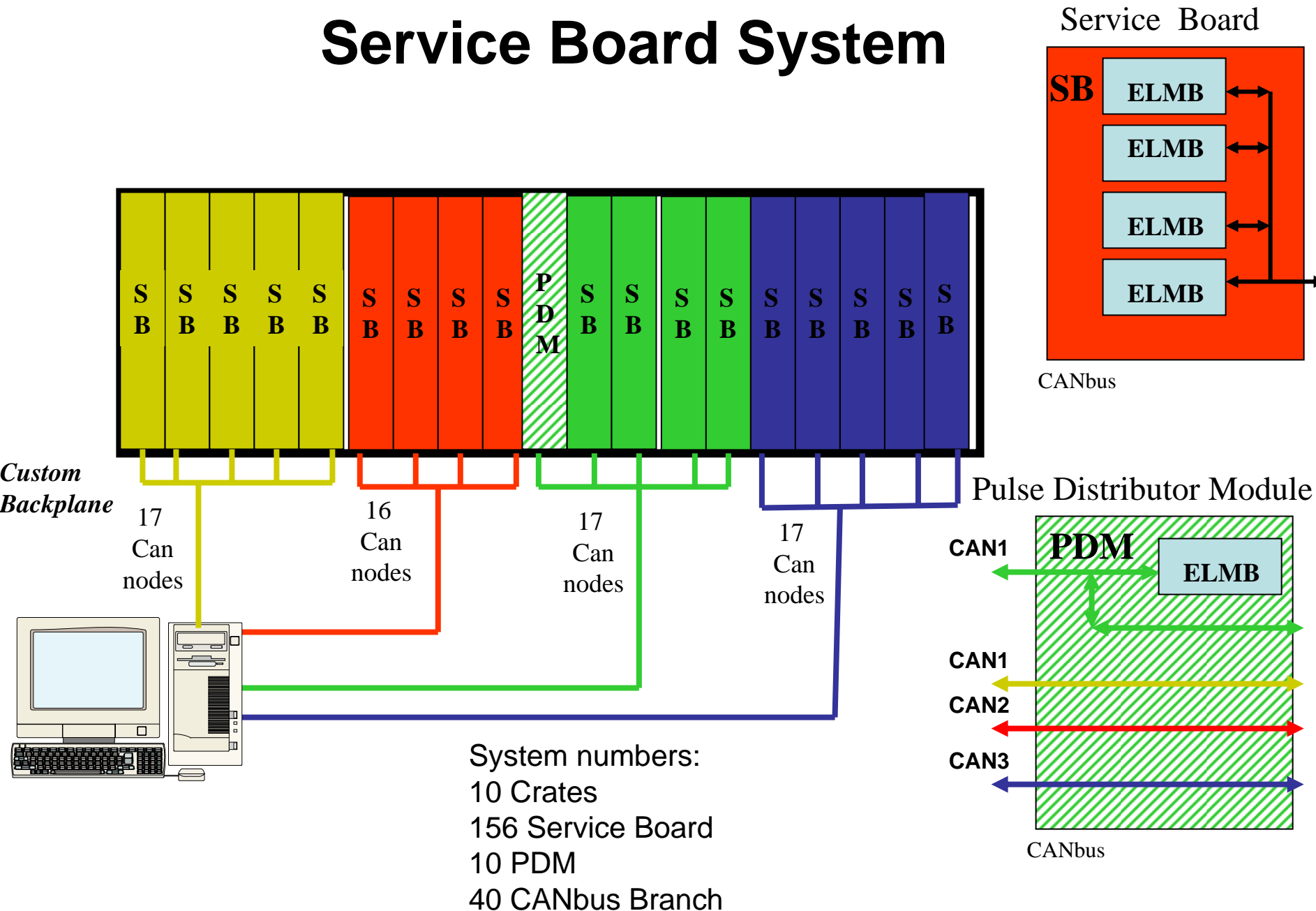
INFN Sezione di Roma



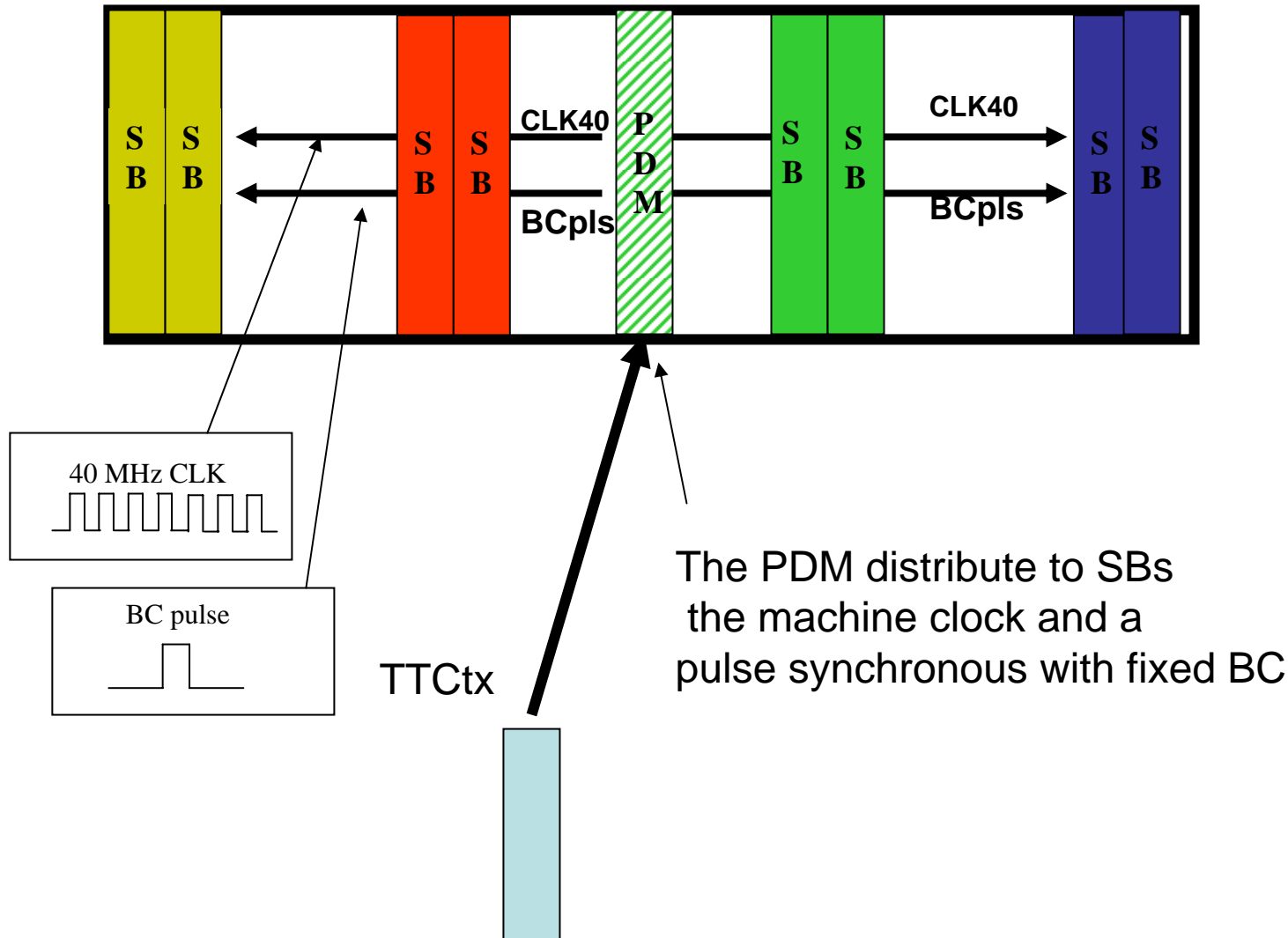
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Sezione di Roma

Service Board System

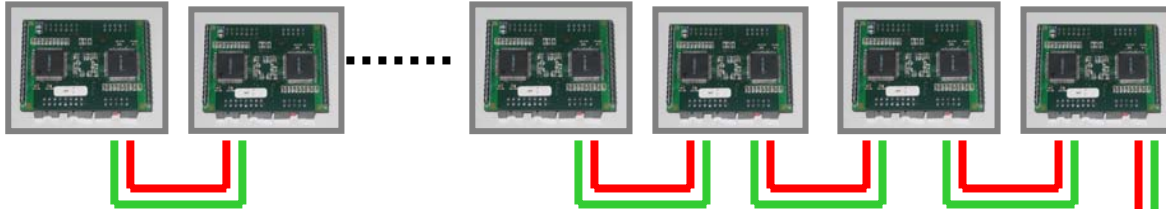


Machine Clock and BC pulse distribution



FEB control and pulse distribution

Up to 8 Cardiac Board for each lvds i2c branch




12 x (I2C+TST signal)

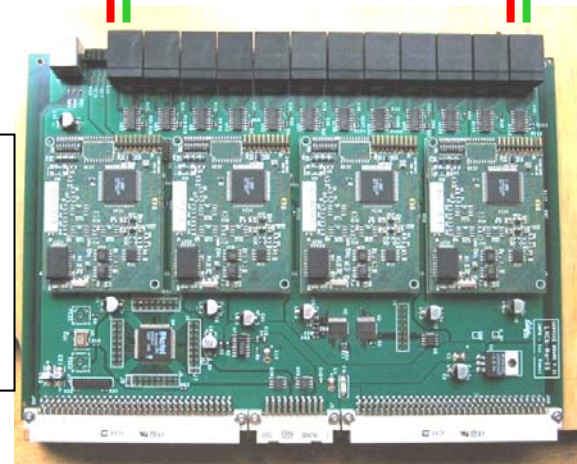
.....

 I2c LVDS signals: SCL, SDAin, SDAout

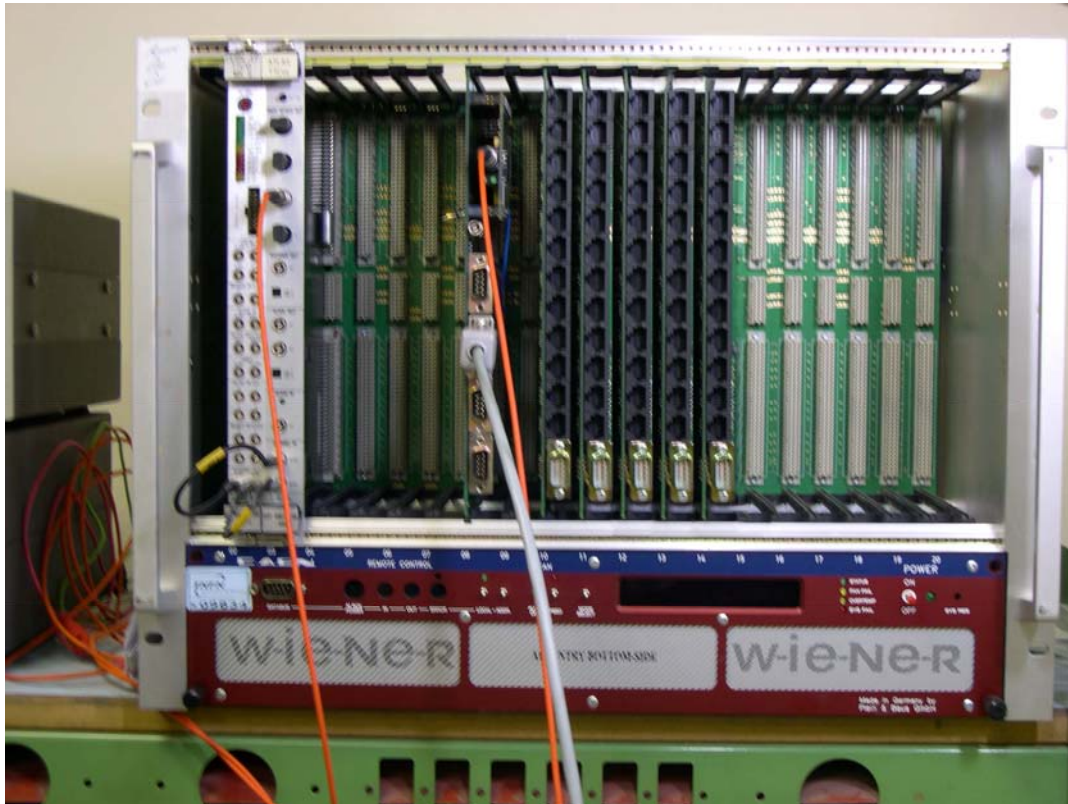
 LVDS TST pulse, TTL Reset

 Read Write Dialog Registers

 Send pulse to measure rate, calibrate DLL, sync pulse, RESET FEB



Service Board Lab Crate



Feb 2005

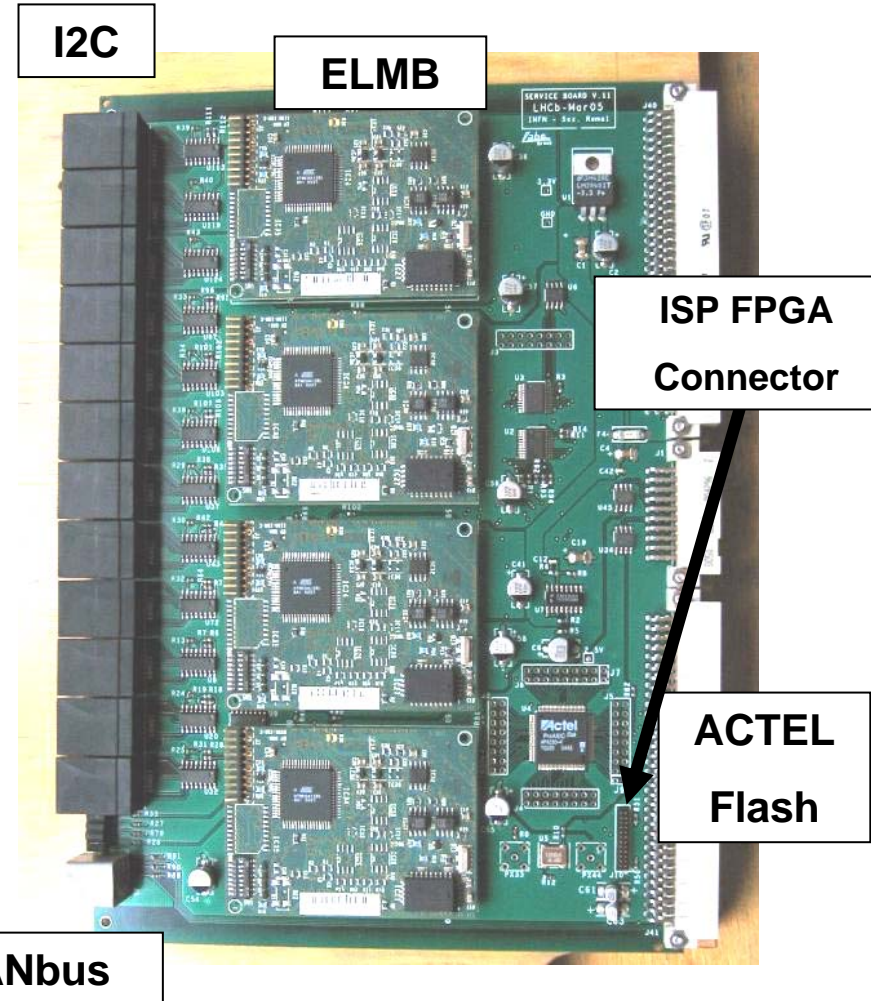
Valerio Bocci PRR July 15 2005

Service Board

(Ten preproduction Boards)

- **Service Boards**

- Program firmware via CANbus
 - One ELMB
 - All ELMBs
- New Features in the ELMB Firmware
 - Address >>> Crate Slot position
 - Scan for DIALOGs (PDO)
- New Flash ACTEL with new features
 - ELMB Reset
 - PDM Reset
 - Tst Pulse logic with pre-scaler (DIALOG testing)
 - Synchronous i2c slave state machine



ELMB128 ATmega128



AVR RISC architecture ATMEL ATmega128

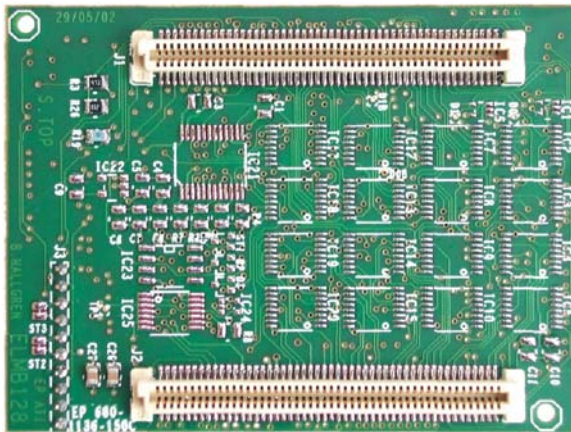
- 0.35 μm technology instead of 0.5 μm
- 128 kbytes of on-chip flash memory,
- 4 kbytes of SRAM
- 4 kbytes of EEPROM.
- In-System Programming via CAN bus using ATmega128 Boot code.

Peripheral Features

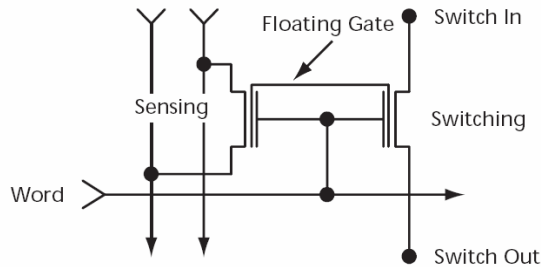
- Full CAN controller interface with PCA82C250

I/O lines available

- 18 digital bi-directional I/O lines , 8 digital output lines ,8 digital inputs or analog inputs with adc



ProASIC^{PLUS} Flash Family FPGAs



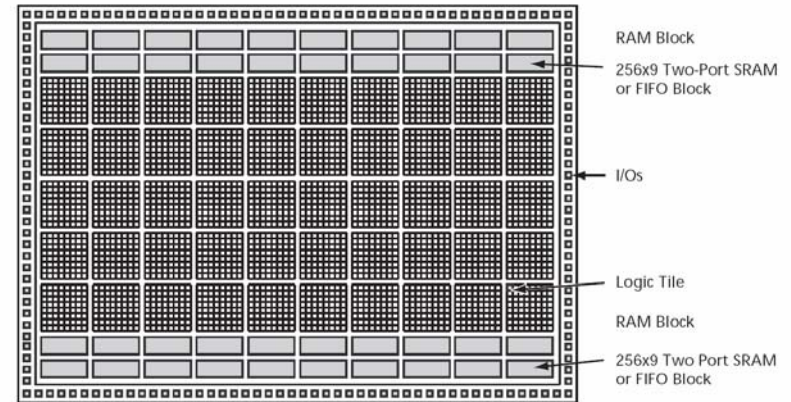
Commercial and Industrial

- 3072- 56320 Tile
- 27 k to 198 kbits of Two-Port SRAM
- 66 to 712 User I/Os

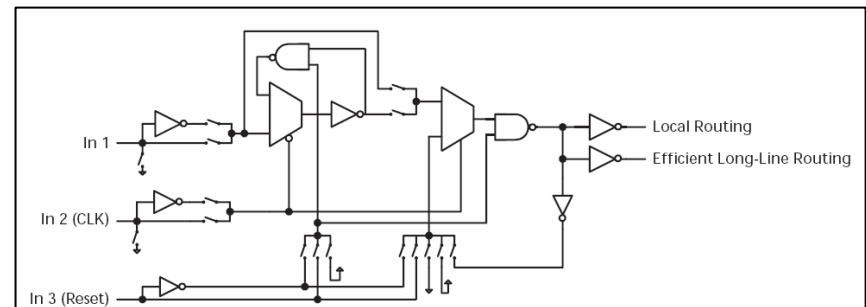
Reprogrammable Flash Technology

- 0.22 μ 4 LM Flash-Based CMOS Process
- Live at Power-Up, Single-Chip Solution
- No Configuration Device Required
- Retains Programmed Design during Power-Down/Up Cycles

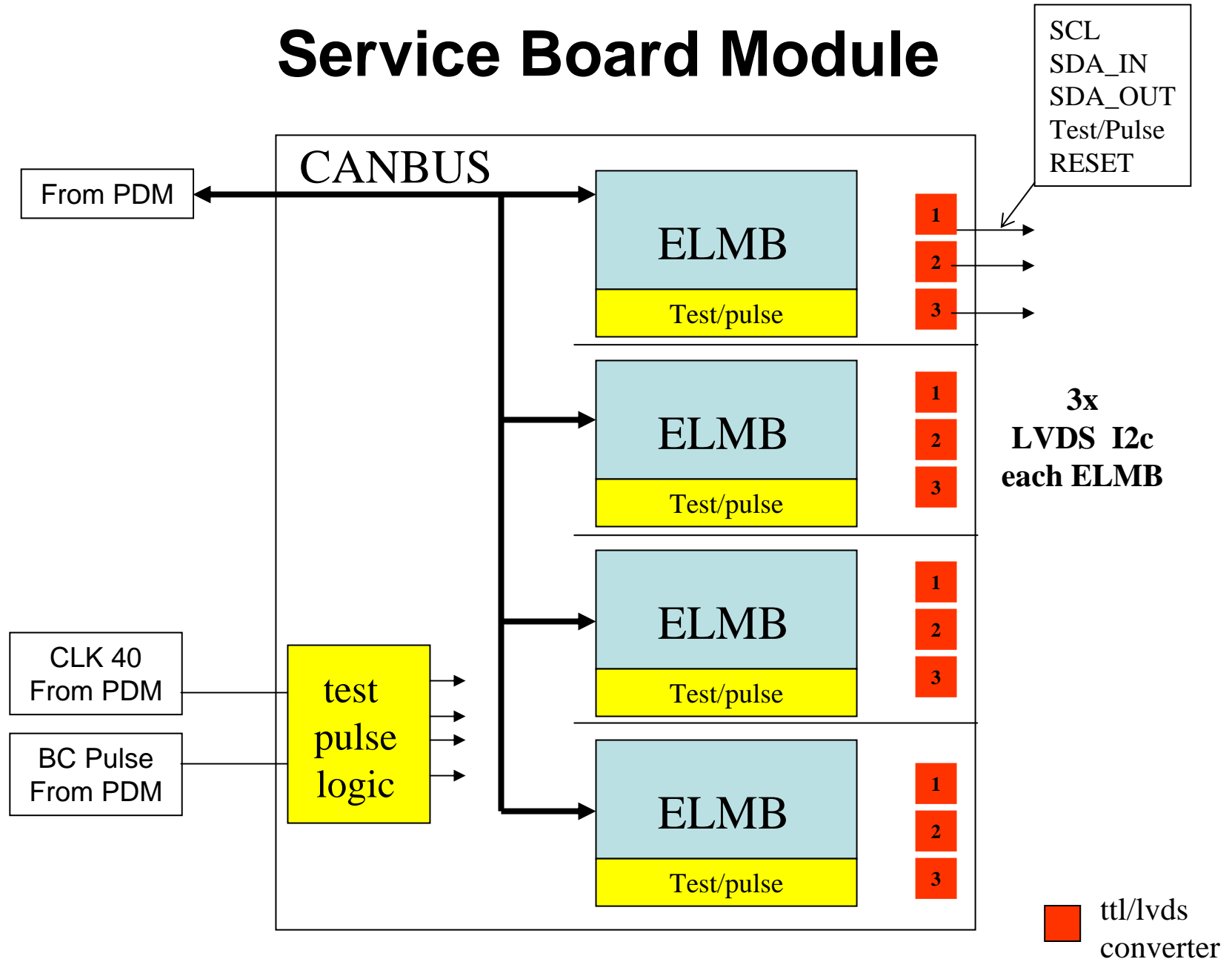
Radiation Tolerant, Flash Cell SEU immune

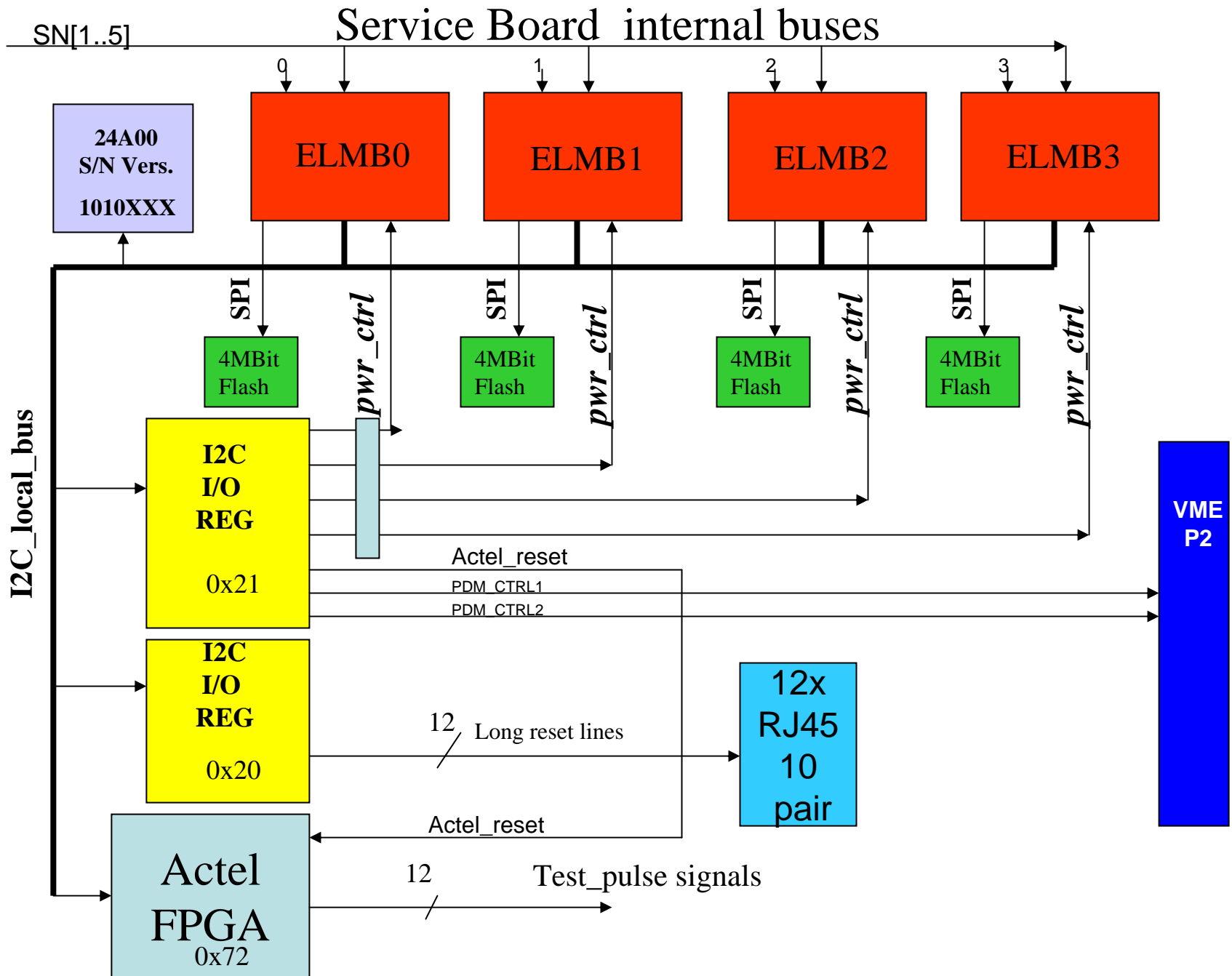


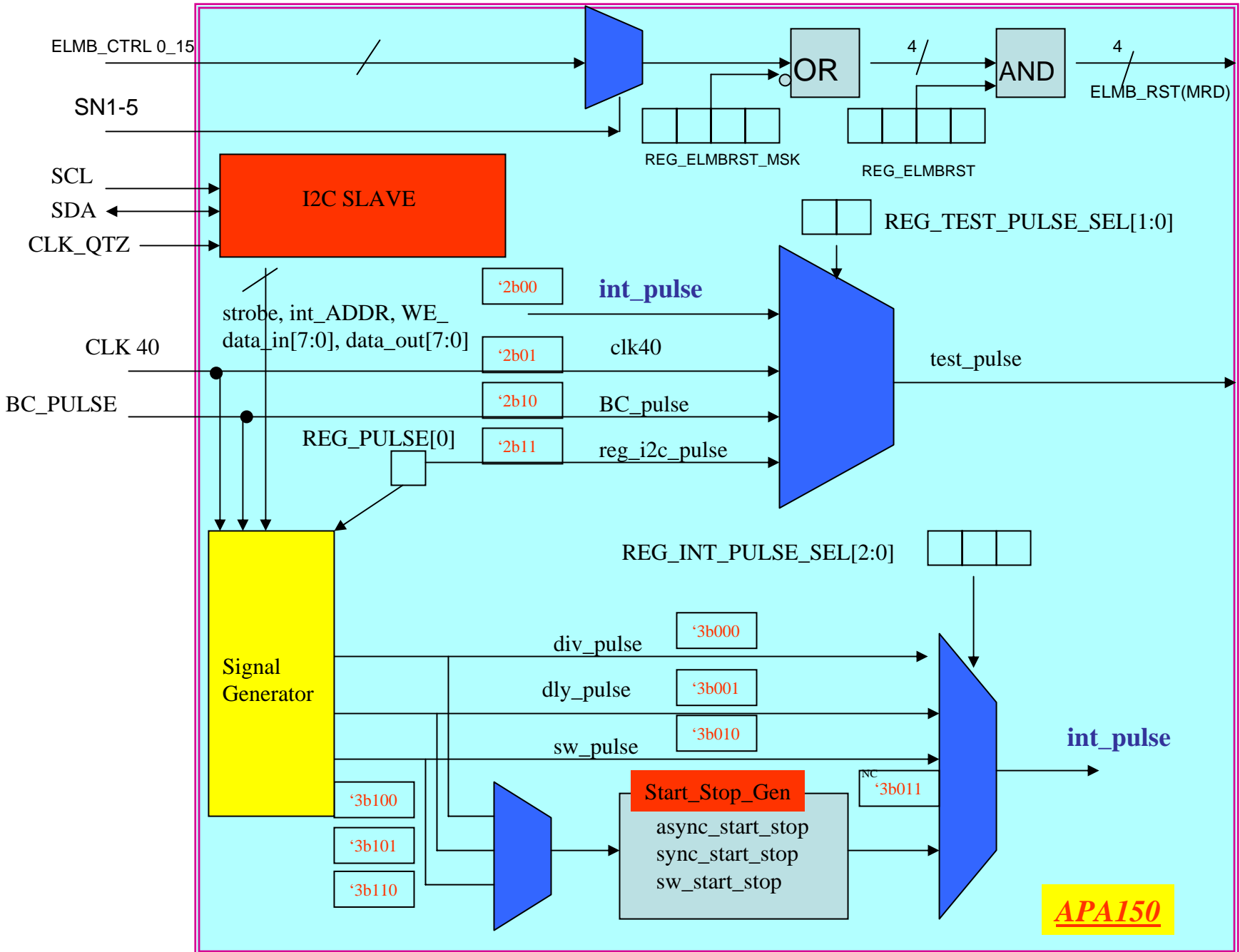
Tile



Service Board Module







SB & DIALOG Control

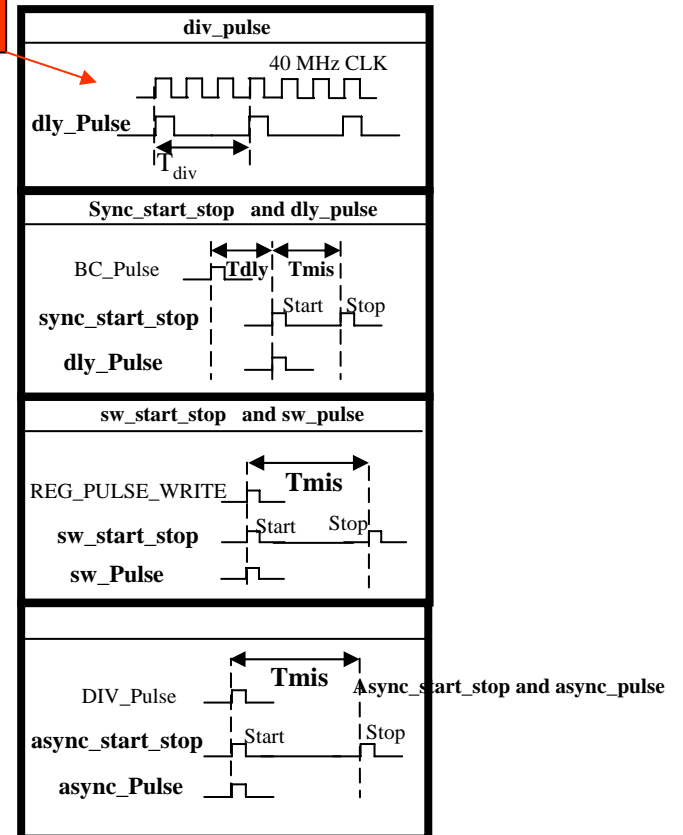
- Control of all DIALOG registers

- Threshold
- Pattern Pulse Generation
- Scaler
- ...

- Access to ACTEL (FPGA) registers

- Test Pulse
 - 40 MHz
 - div_pulse
 - delay_pulse
 - sw_start_stop
 - ...
- Reset ELMB
- Mask for Test Pulse

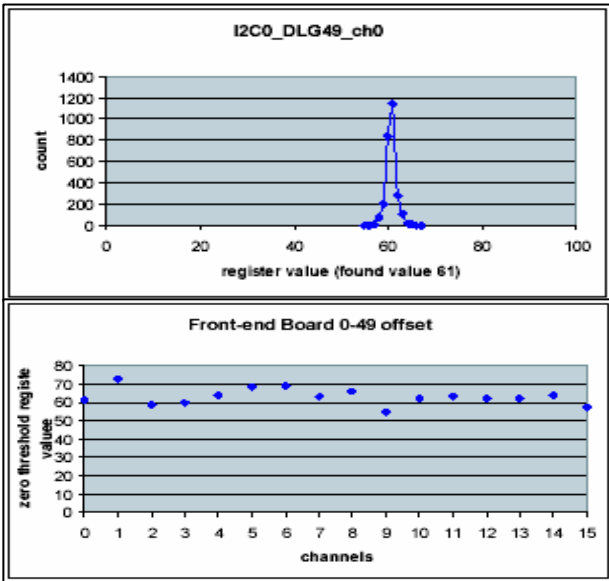
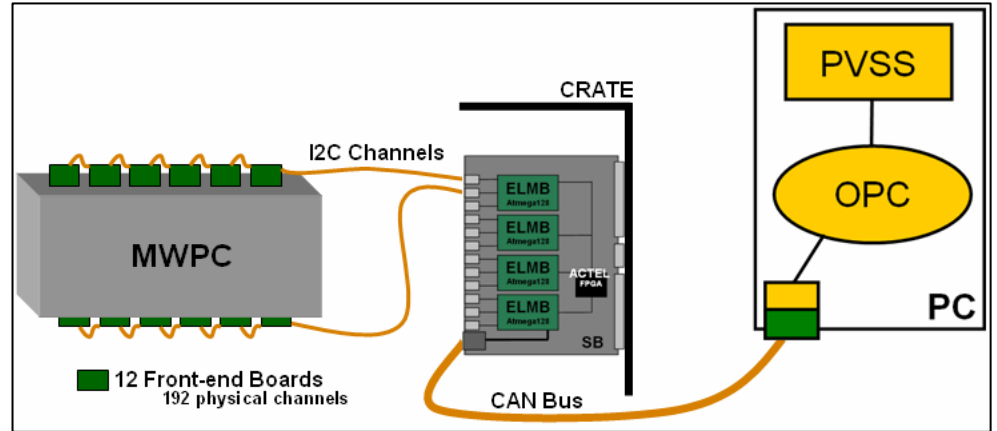
Pre-scaler



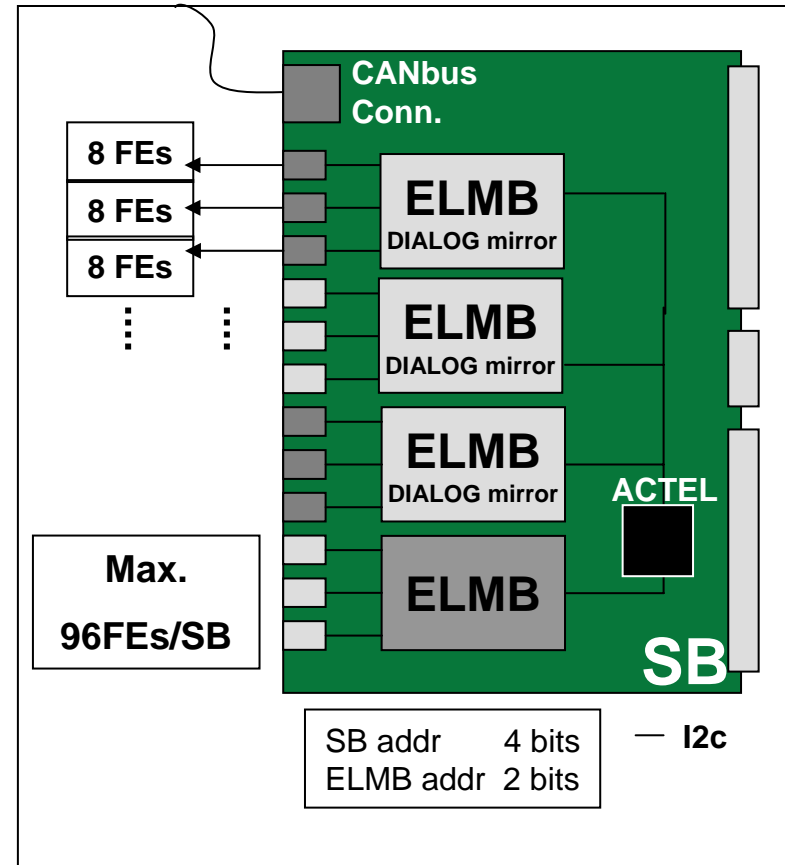
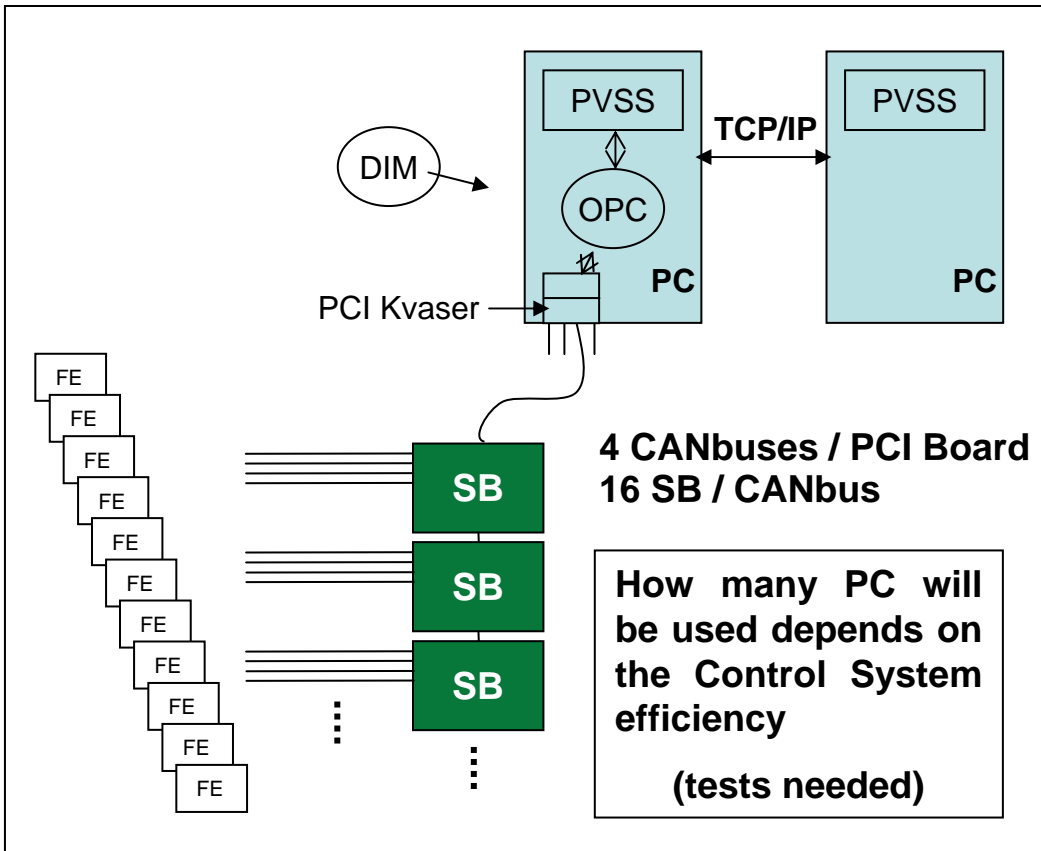
Test Using GIF Facilities (July 2004)

Test of Frascati MWPC Chamber

- 192 channels (12 FEBs)
- Control of all registers – *ok*
- Calibration of all channels – *ok*
- Reset Ctrl – *needed and implemented*



Control System Overview



SB Front-end Testing

- **i2c lvds + ctrl signals**

- SCL
- SDA_IN
- SDA_OUT
- Test Pulse
- RESET

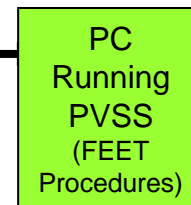
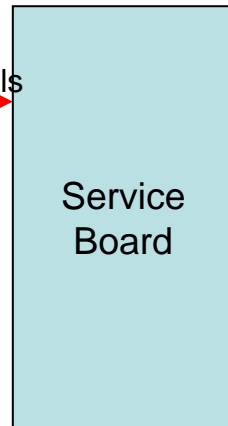
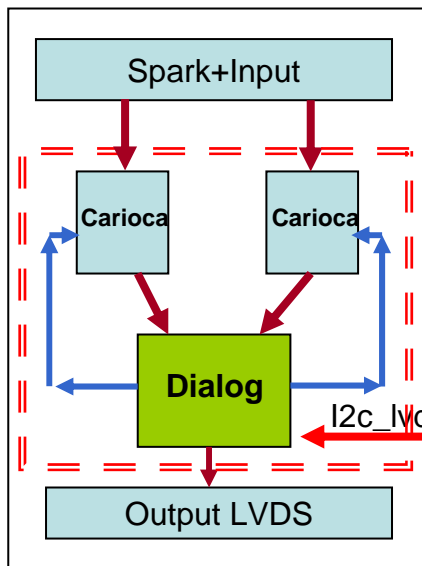
- **CARDIAC Test**

- **DIALOG Functionality**

- Threshold
- Pulse Generator
- Test Dialog Channels
 - Pattern Generator
 - Scaler
 - Tst Pulse
 - ...

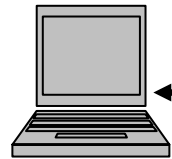
- **CARIOCA Test**

- If all channels are responding
- Rate Method (?)
- ...



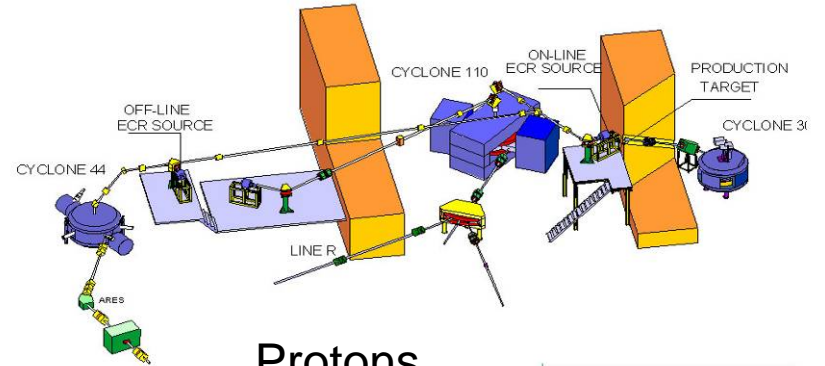
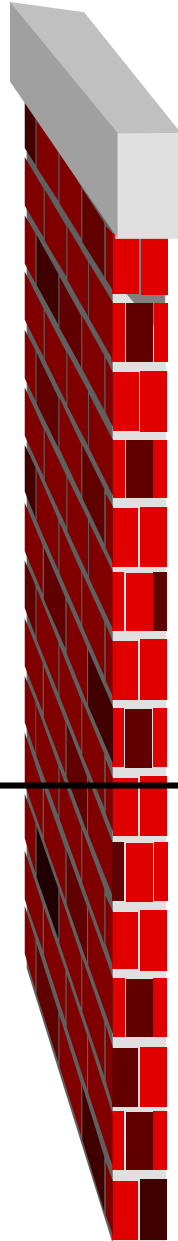
- ← Blue arrow: Carioca threshold, pulse, charge dac
- Red arrow: Signal processed from carioca (Analog) and then from dialog (digital)
- ↔ Red double arrow: I2c lvds+pulse signal

Voltage regulators test

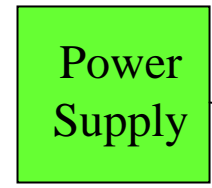


Ethernet

- Data logging of current and voltage measurements to reveal SEU and total dose related effects

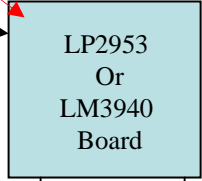


Protons
60 MeV



1 m

Rad Area



RS232

RS232

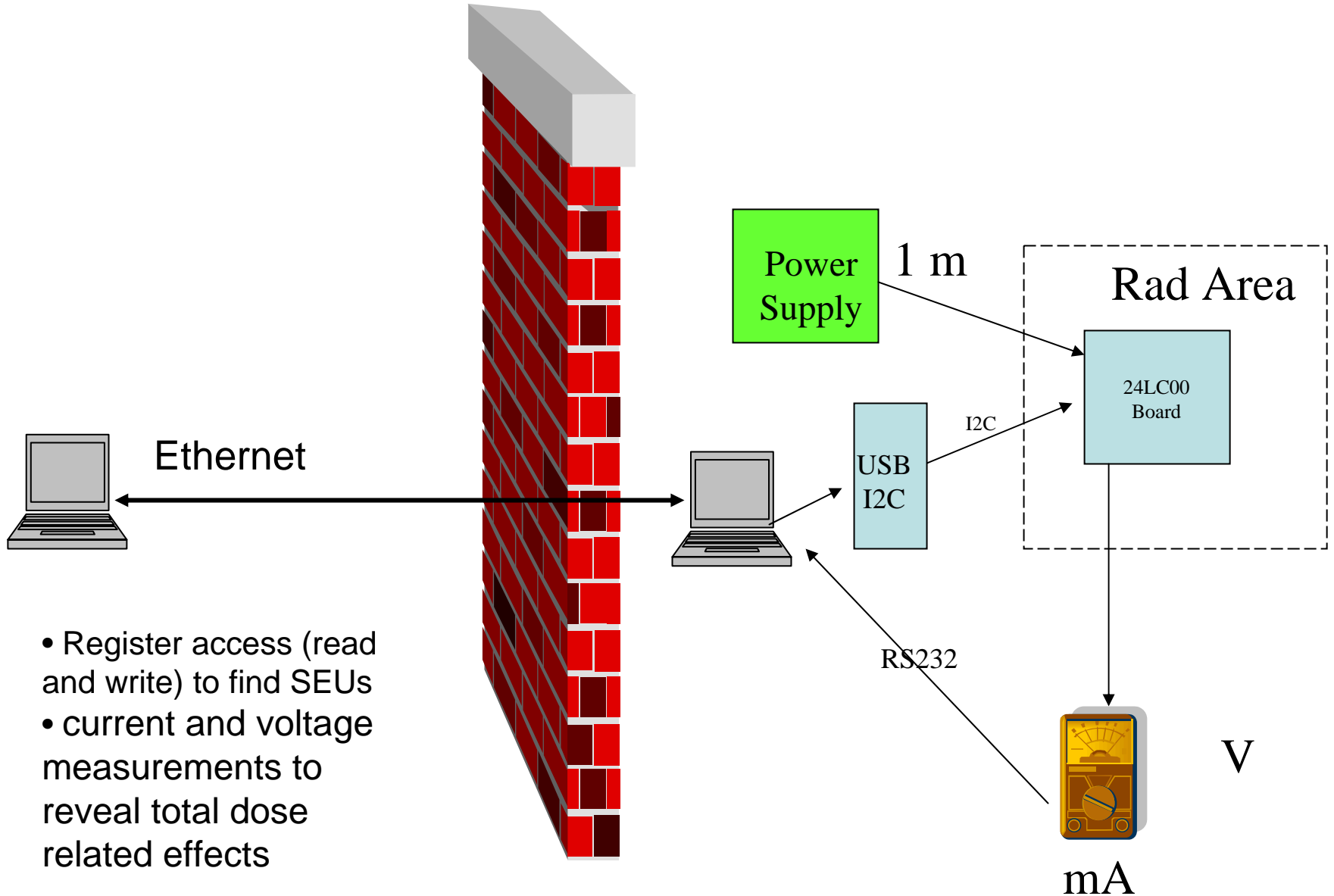


V



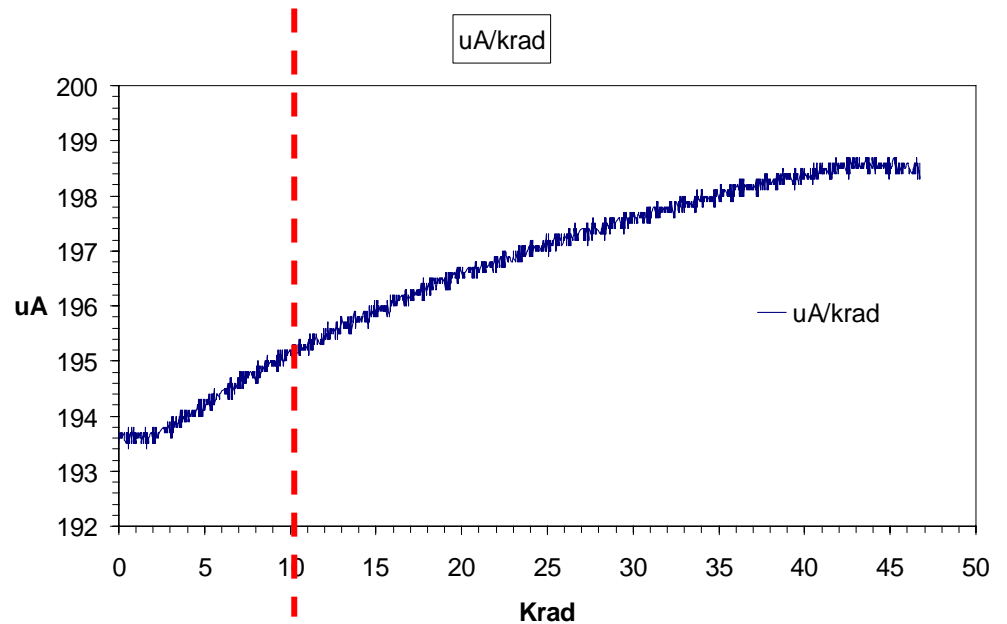
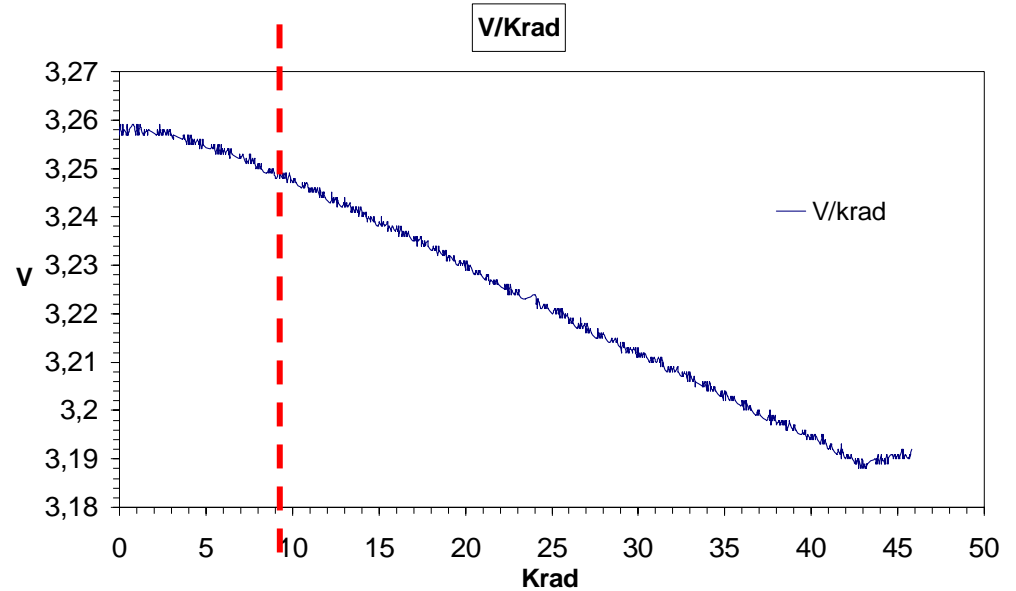
mA

Flash memory test



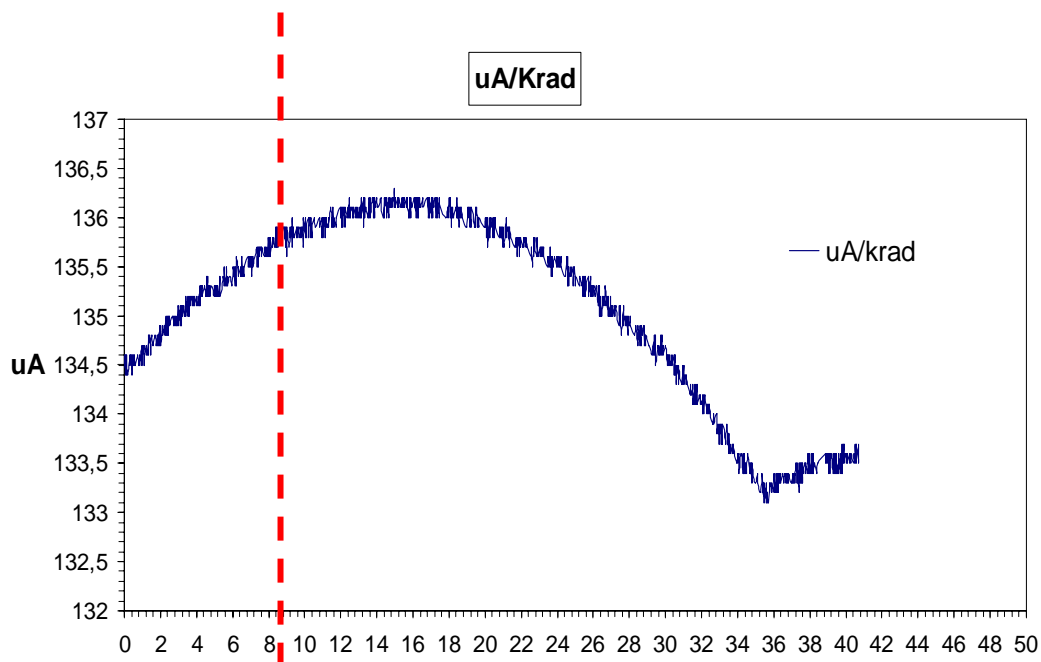
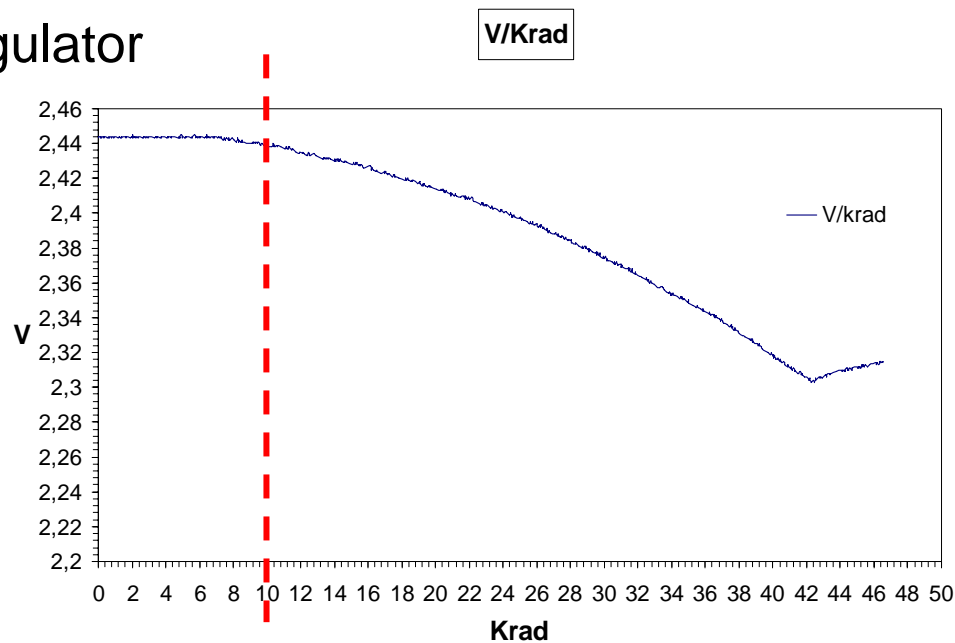
LM3940: 3.3 V output voltage regulator

- **Tests: ok**
- No voltage and current peaks
- Voltage within operating range
- Current variations below 2uA
- Device break-point well beyond 10Krad



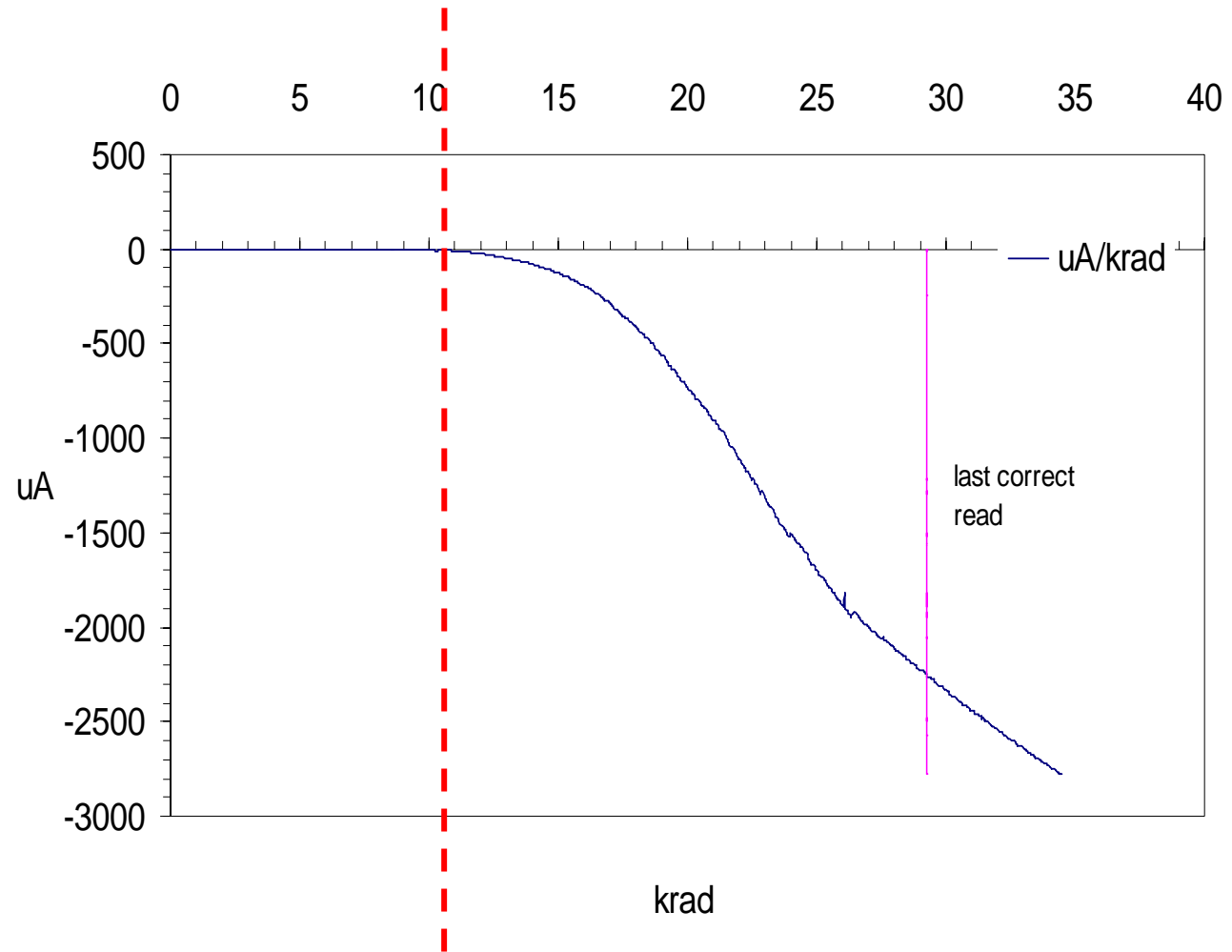
LP2953 : 2.5 V output voltage regulator

- **Tests: ok**
- No voltage and current peaks
- Voltage within operating range
- Current variations below 2uA
- Device break-point well beyond 10Krad



24LC00 :128 Bit Flash PROM

- No SEU found
- Reliable operation up to ~30Krad equiv.
- No issues for foreseeable total dose values (<10Krad)



Atmel Flash SEE Test

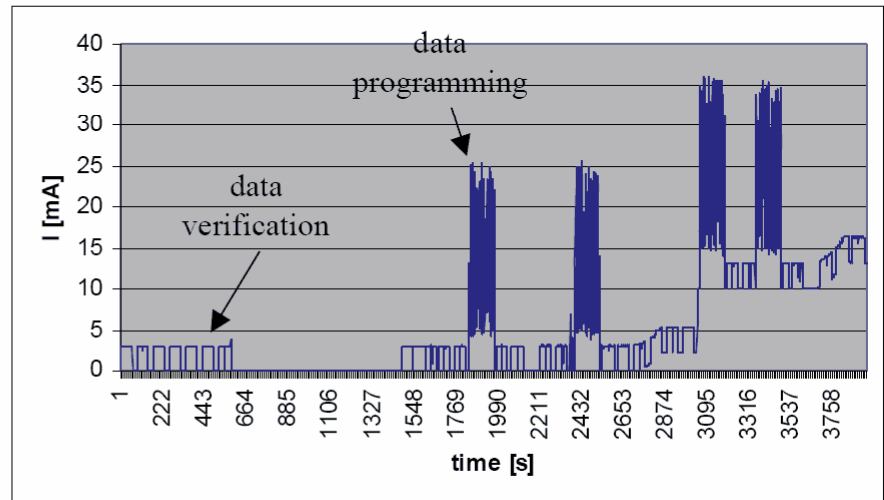
- Flux applied: $5 \cdot 10^8$ h/cm²/s
- Fluence: $2 \cdot 10^{11}$ h/cm²
- The chip was monitored during data programming and verification (0101... pattern was used)
- No errors on flash memory
- 83, 83, 38, 56 bit errors on each of the RAMs after the applied fluence
- Power consumption increase due to total dose effects
- For a bigger fluence the serial interface stopped working correctly.

AT45DB041B features:

- 3.3 V
- serial interface flash memory
- SPI compatible
- 4,325,376 bits of memory
- two 264-byte SRAM data buffers

RESULTS:

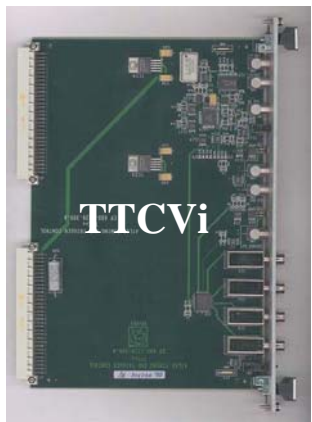
- 4 chips tested
- Flash soft $SEU_f < 6.8 \cdot 10^{-9} s^{-1}$
- RAM soft $SEU_f = 5.6 \cdot 10^{-7} s^{-1}$
- $2 \cdot 10^{11} h/cm^2 \sim 2 \cdot 14 krad = 28 krad$



PDM

Pulse Distribution Module

- Distribute CANbus to Backplane
- Receive the timing information form TTCtx
- Distribute Machine Clock
- Produce a pulse synchronous with specified BC number
- An ELMB setting up TTCrx ,PDM FPGA,Reset hanging SB



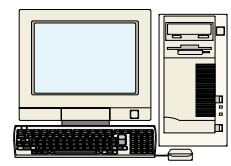
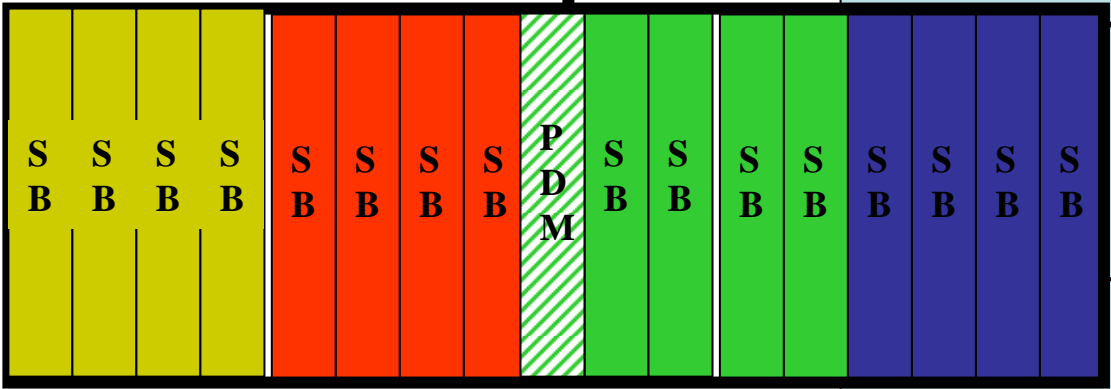
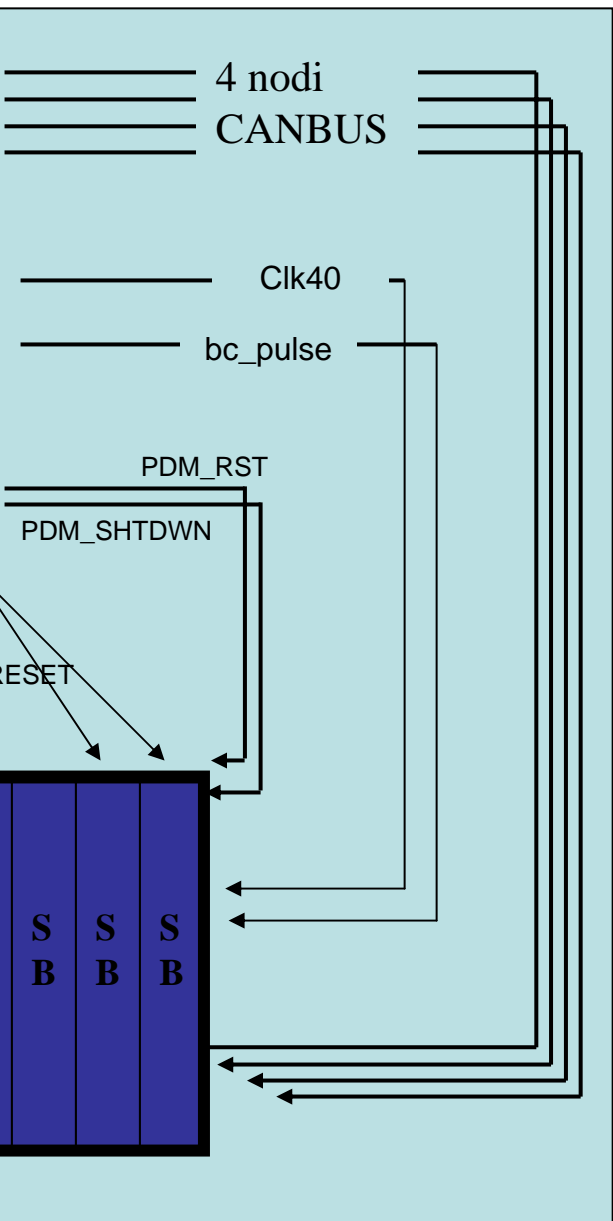
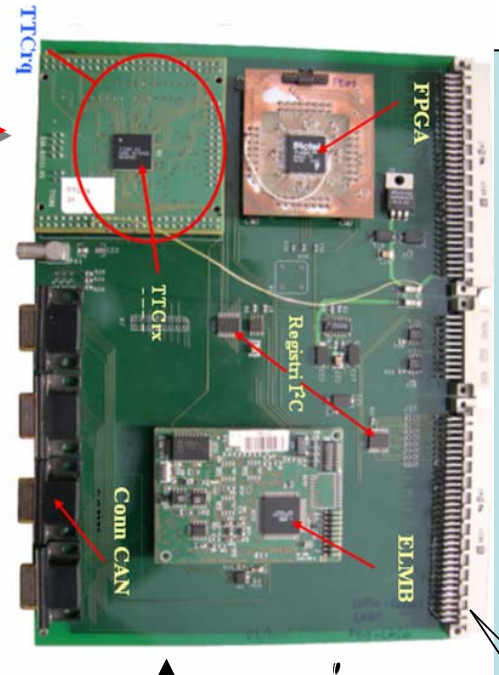
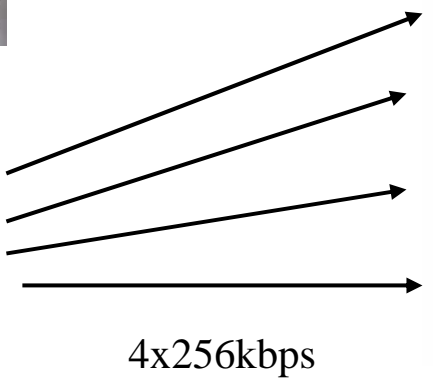
Pulse Distribution Module

Custom Backplane

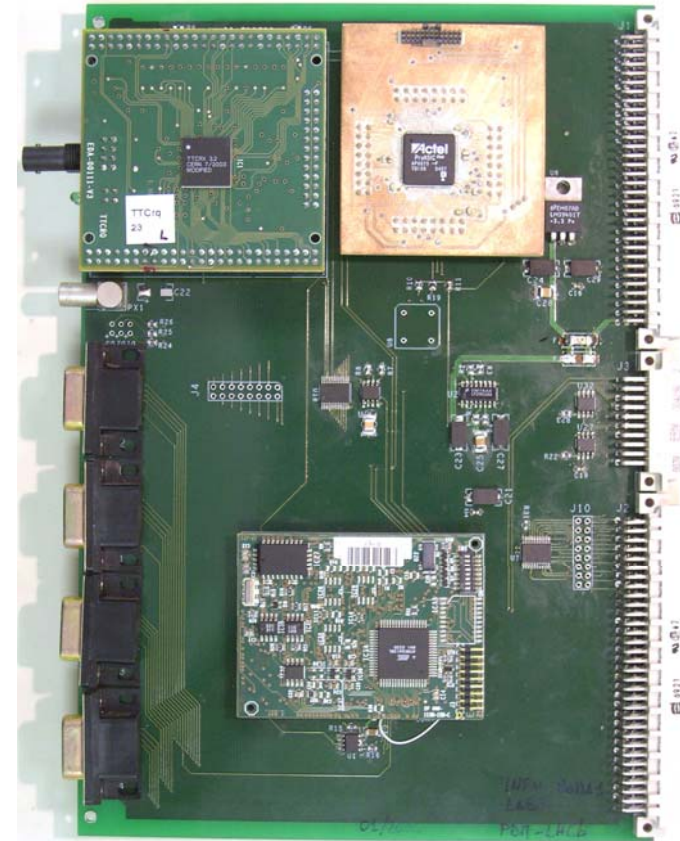
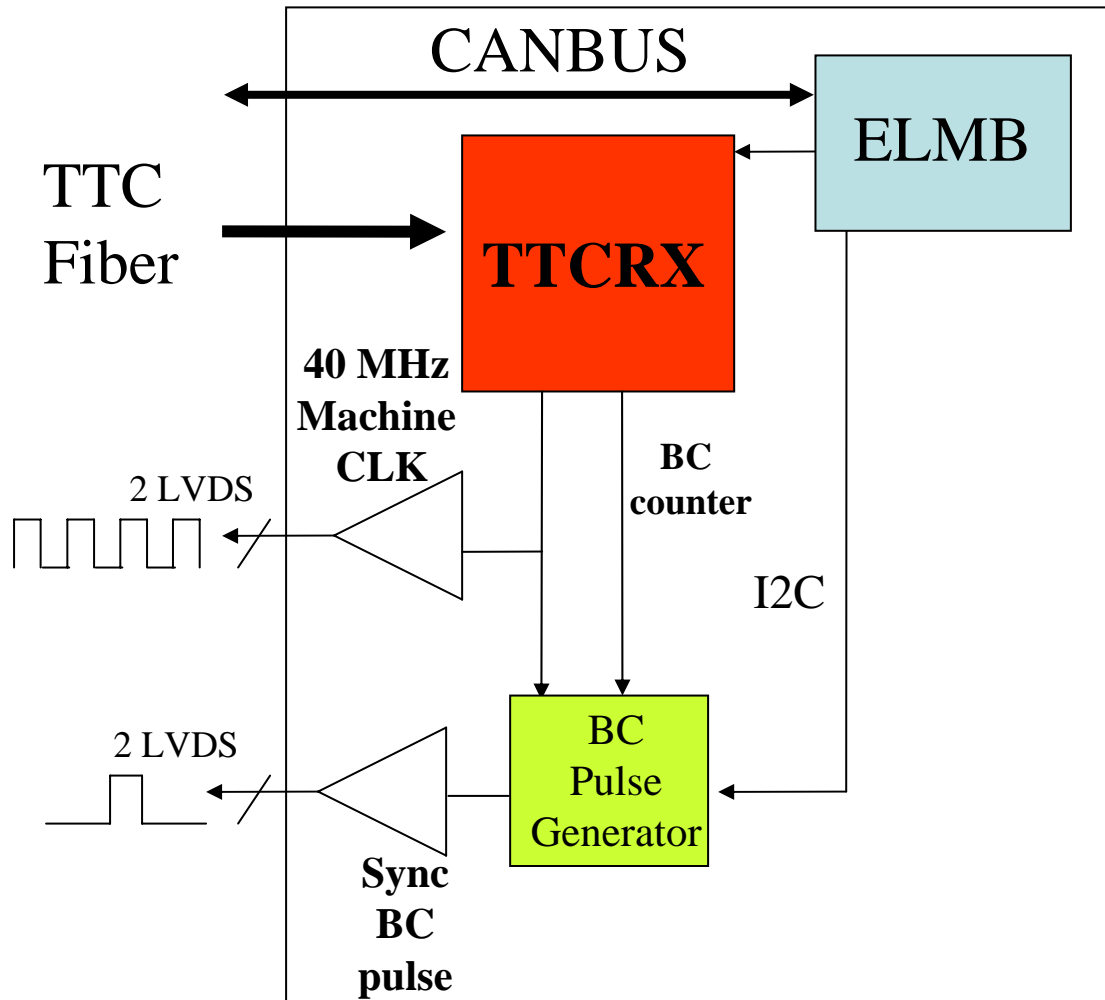
TTC
Fiber



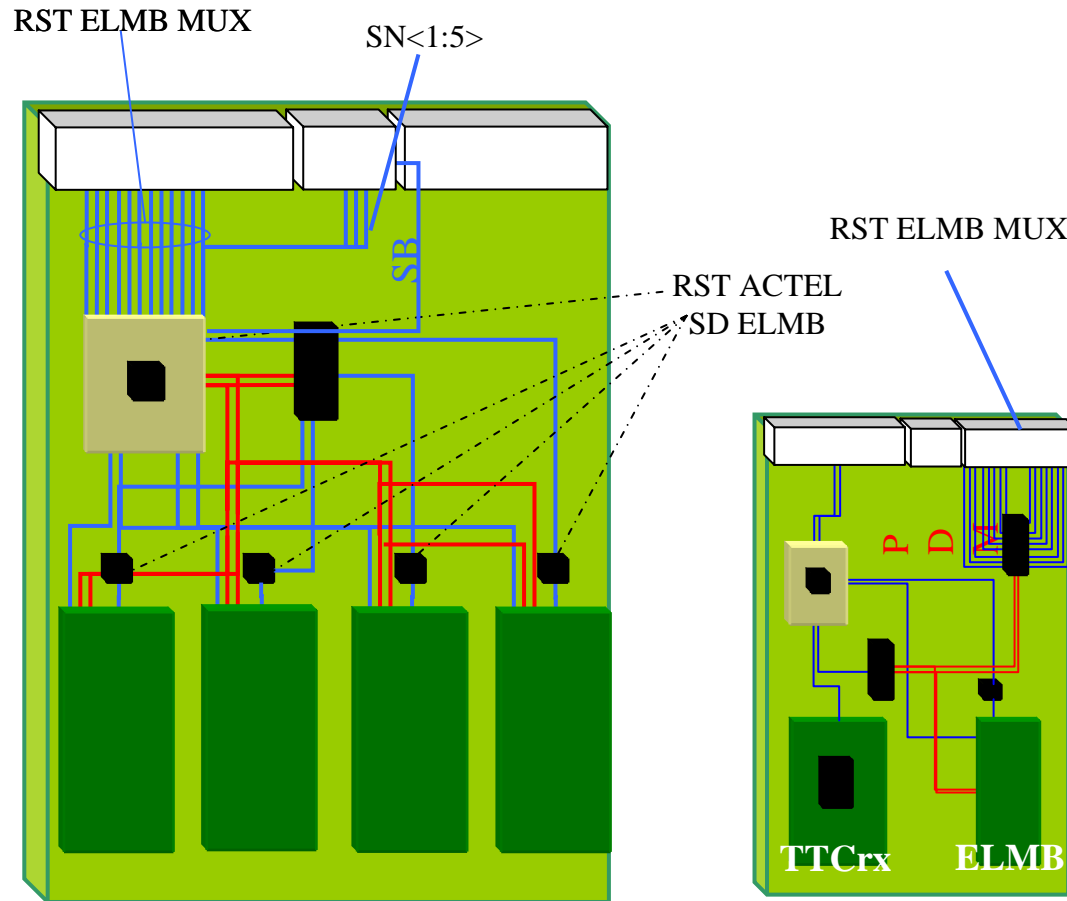
4CANBUS
Nodes
↑
PCI Board
Kvaser CAN



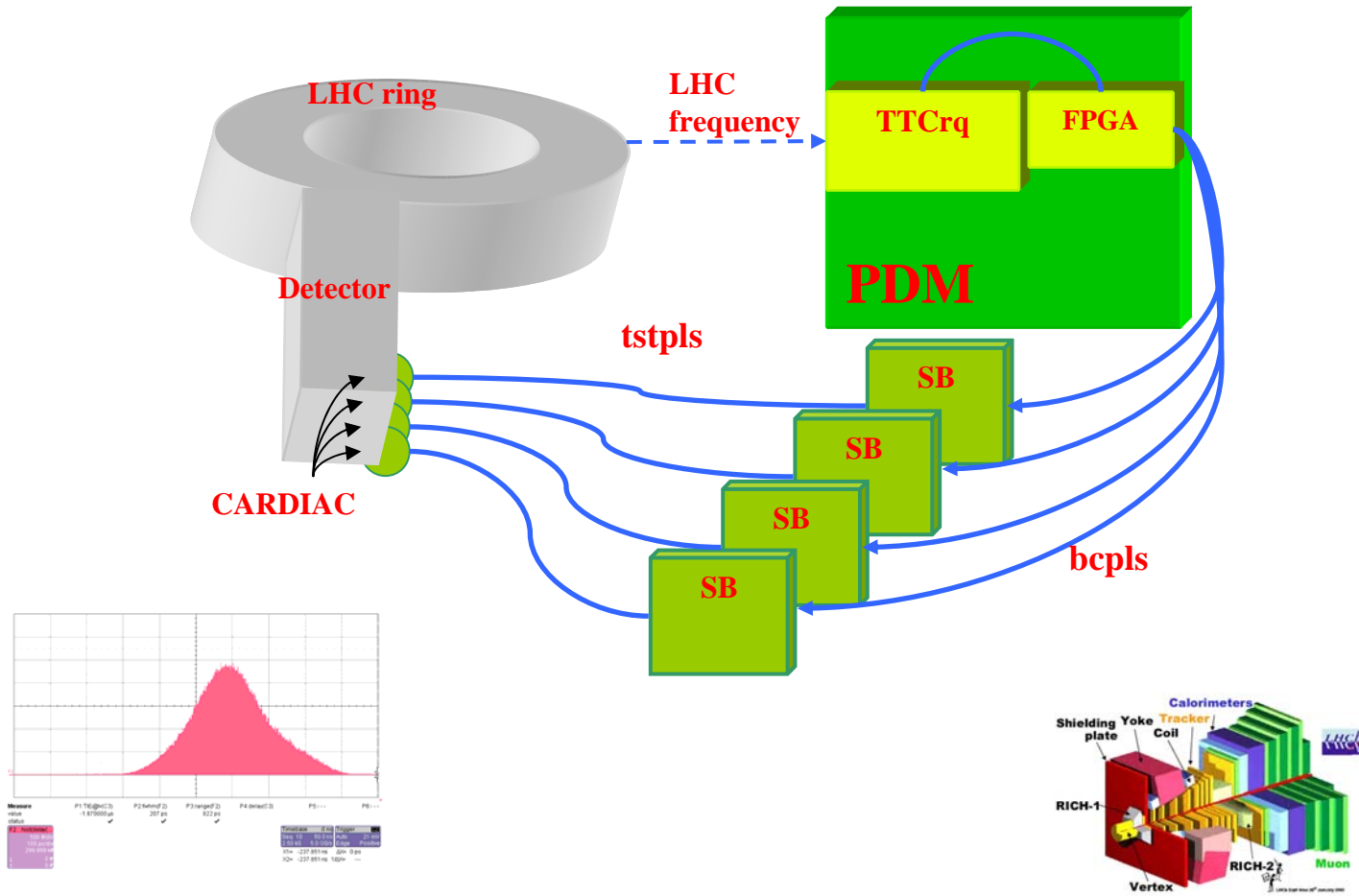
Pulse Distribution Module



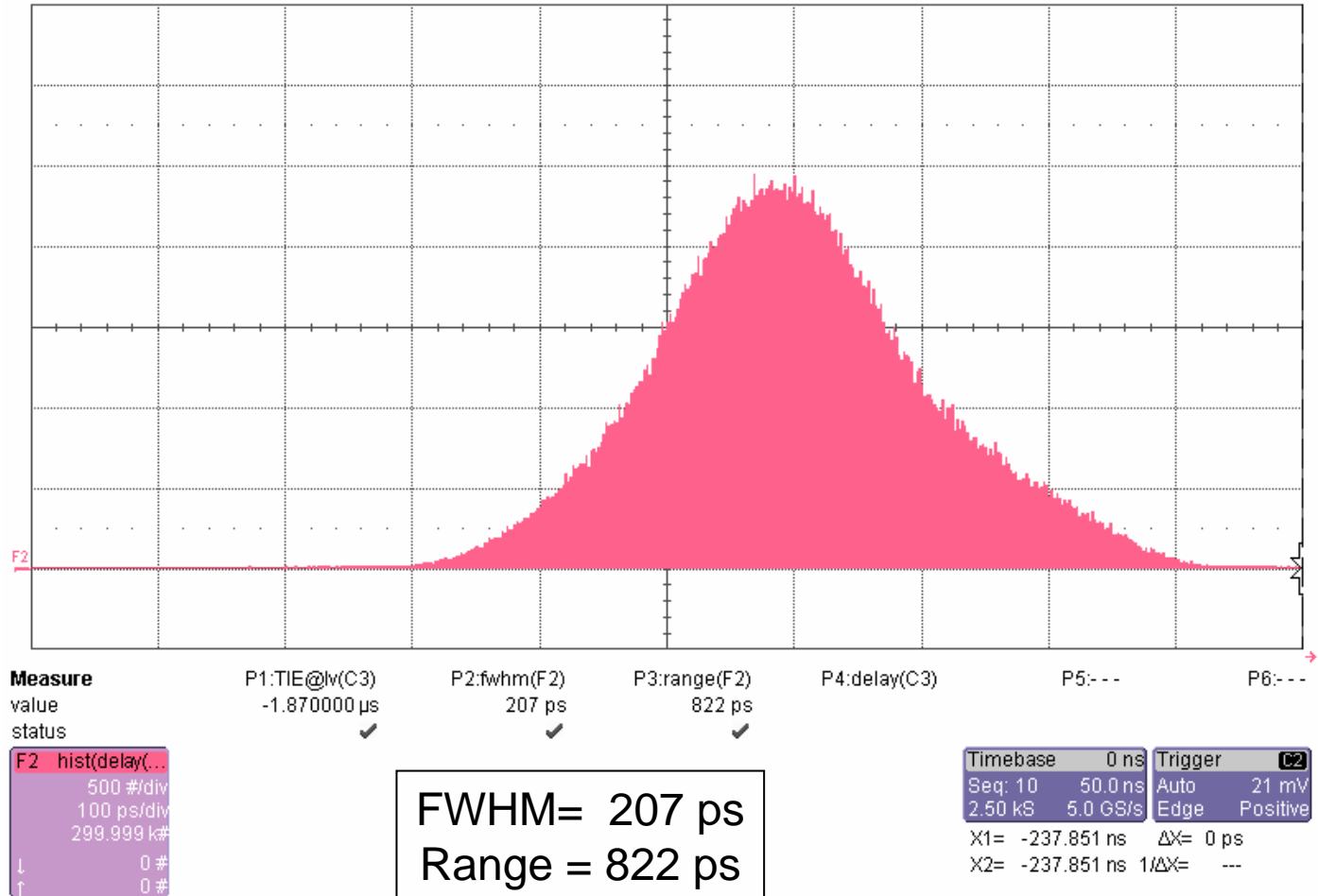
Shut down and Reset *SB* and *PDM*



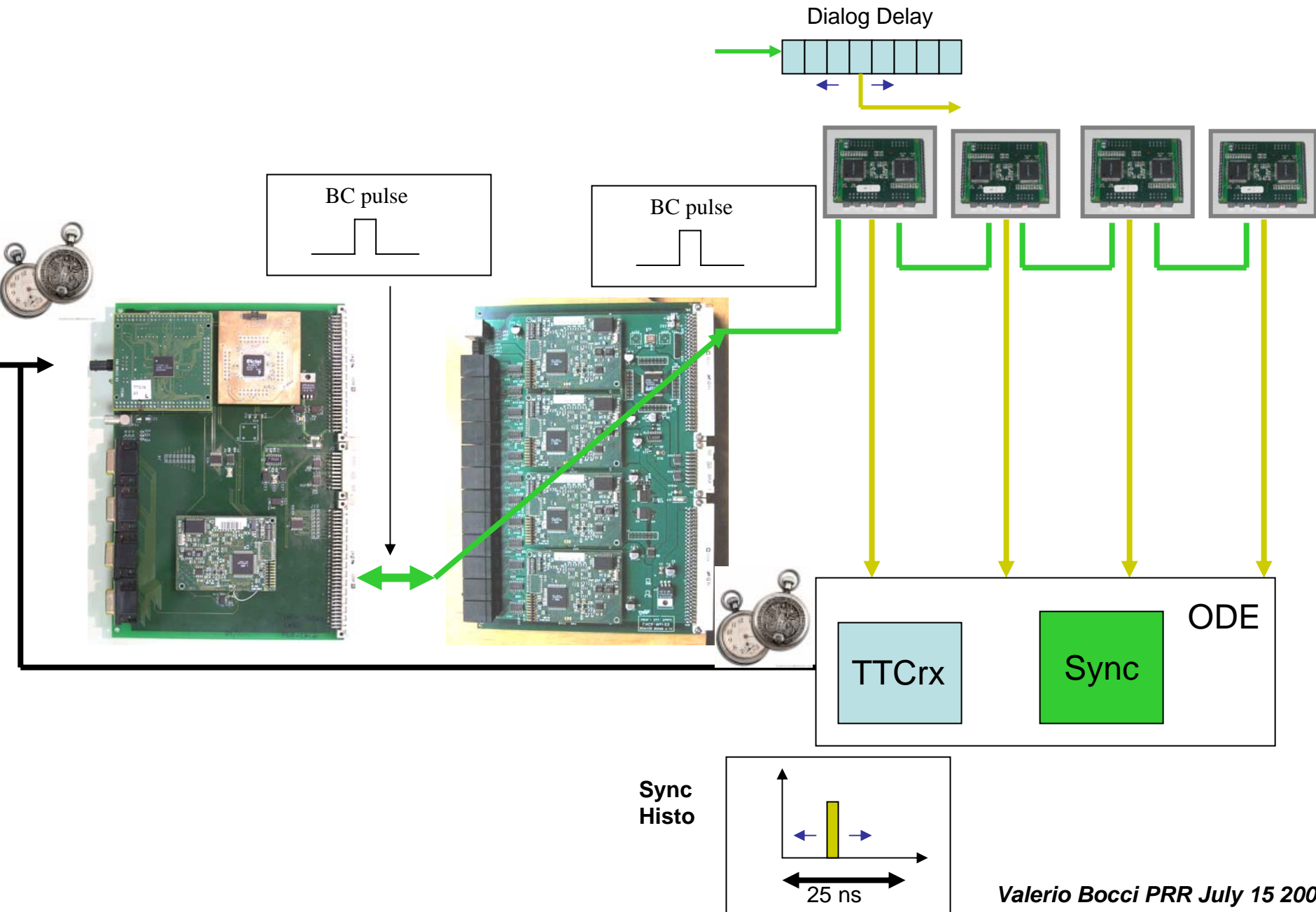
PDM Pulse path



TTCvi->TTCRx>PDM->SB->I2CLVDS Jitter



Fast coarse Time Alignment (Without physics)



Conclusions

- Service Board prototype was useful tool for chamber test
- The FPGA flash was a big advantage
- We have 10 preproduction board under test

- PDM prototype is working fine we want to finalize the design with new feature.
- We decide to design a custom backplane instead of a customized vme430 (cost reason)